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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	2880
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	174
Number of Gates	48000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx32a-1pq208i

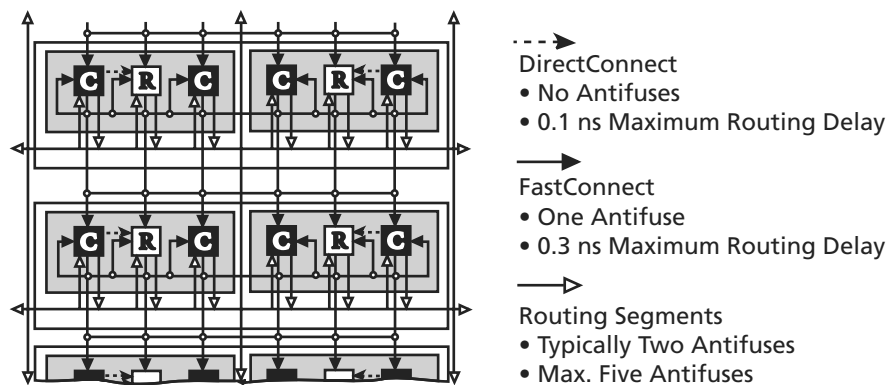


Figure 1-5 • DirectConnect and FastConnect for Type 1 SuperClusters

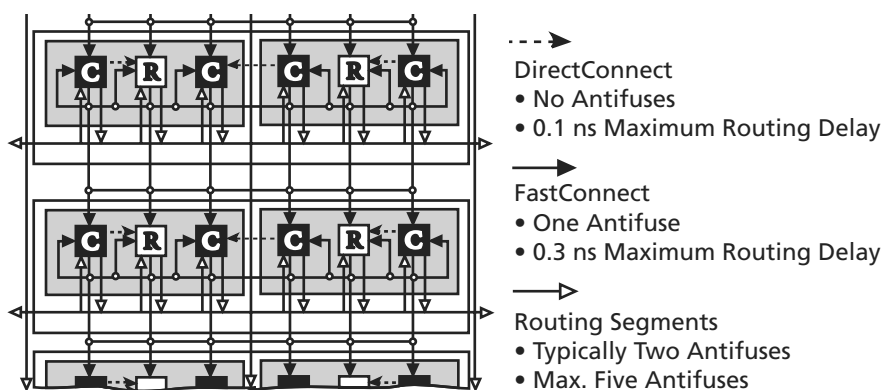


Figure 1-6 • DirectConnect and FastConnect for Type 2 SuperClusters

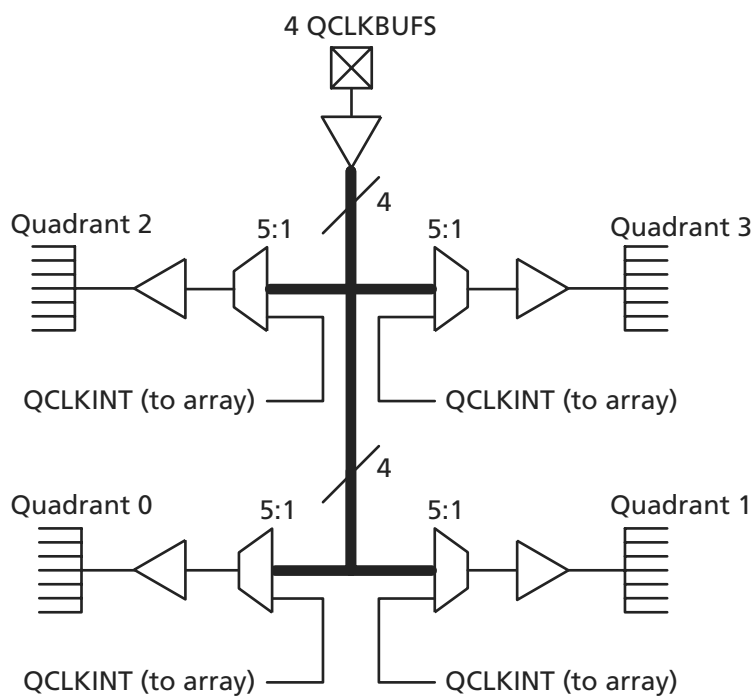


Figure 1-9 • SX-A QCLK Architecture

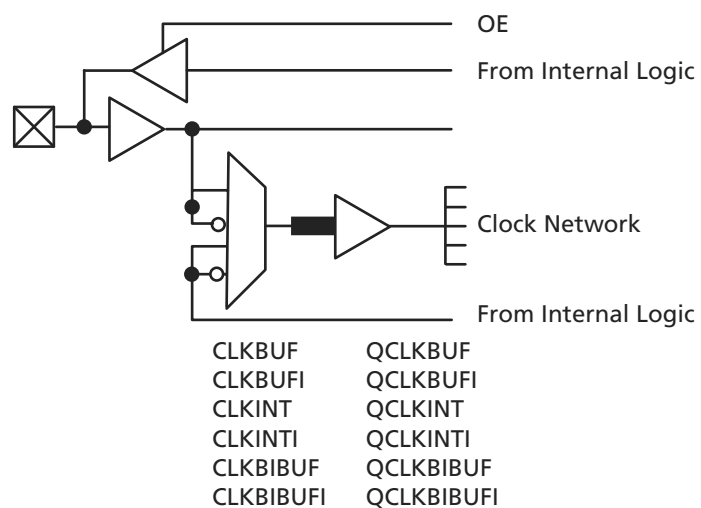


Figure 1-10 • A54SX72A Routed Clock and QCLK Buffer

Probing Capabilities

SX-A devices also provide an internal probing capability that is accessed with the JTAG pins. The Silicon Explorer II diagnostic hardware is used to control the TDI, TCK, TMS, and TDO pins to select the desired nets for debugging. The user assigns the selected internal nets in Actel Silicon Explorer II software to the PRA/PRB output pins for observation. Silicon Explorer II automatically places the device into JTAG mode. However, probing functionality is only activated when the TRST pin is driven high or left floating, allowing the internal pull-up resistor to pull TRST High. If the TRST pin is held Low, the TAP controller remains in the Test-Logic-Reset state so no probing can be performed. However, the user must drive the TRST pin High or allow the internal pull-up resistor to pull TRST High.

When selecting the **Reserve Probe Pin** box as shown in Figure 1-12 on page 1-9, direct the layout tool to reserve the PRA and PRB pins as dedicated outputs for probing. This **Reserve** option is merely a guideline. If the designer assigns user I/Os to the PRA and PRB pins and selects the **Reserve Probe Pin** option, Designer Layout will override the **Reserve Probe Pin** option and place the user I/Os on those pins.

To allow probing capabilities, the security fuse must not be programmed. Programming the security fuse disables the JTAG and probe circuitry. Table 1-9 summarizes the possible device configurations for probing once the device leaves the Test-Logic-Reset JTAG state.

Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved)

JTAG Mode	TRST ¹	Security Fuse Programmed	PRA, PRB ²	TDI, TCK, TDO ²
Dedicated	Low	No	User I/O ³	JTAG Disabled
	High	No	Probe Circuit Outputs	JTAG I/O
Flexible	Low	No	User I/O ³	User I/O ³
	High	No	Probe Circuit Outputs	JTAG I/O
		Yes	Probe Circuit Secured	Probe Circuit Secured

Notes:

1. If the TRST pin is not reserved, the device behaves according to TRST = High as described in the table.
2. Avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, input signals will not pass through these pins and may cause contention.
3. If no user signal is assigned to these pins, they will behave as unused I/Os in this mode. Unused pins are automatically tristated by the Designer software.

SX-A Probe Circuit Control Pins

SX-A devices contain internal probing circuitry that provides built-in access to every node in a design, enabling 100% real-time observation and analysis of a device's internal logic nodes without design iteration. The probe circuitry is accessed by Silicon Explorer II, an easy to use, integrated verification and logic analysis tool that can sample data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

The Silicon Explorer II tool uses the boundary-scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the

PRA/PRB pins for observation. Figure 1-13 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

In order to preserve device probing capabilities, users should avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, critical input signals through these pins are not available. In addition, the security fuse must not be programmed to preserve probing capabilities. Actel recommends that you use a 70 Ω series termination resistor on every probe connector (TDI, TCK, TMS, TDO, PRA, PRB). The 70 Ω series termination is used to prevent data transmission corruption during probing and reading back the checksum.

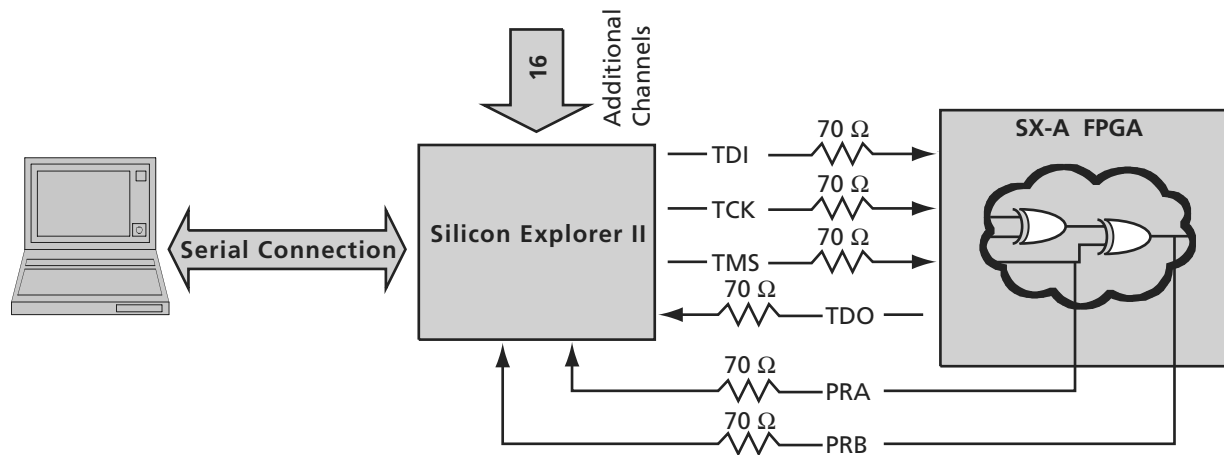


Figure 1-13 • Probe Setup

Detailed Specifications

Operating Conditions

Table 2-1 • Absolute Maximum Ratings

Symbol	Parameter	Limits	Units
V_{CCI}	DC Supply Voltage for I/Os	−0.3 to +6.0	V
V_{CCA}	DC Supply Voltage for Arrays	−0.3 to +3.0	V
V_I	Input Voltage	−0.5 to +5.75	V
V_O	Output Voltage	−0.5 to + V_{CCI} + 0.5	V
T_{STG}	Storage Temperature	−65 to +150	°C

Note: *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the "Recommended Operating Conditions".

Table 2-2 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Units
Temperature Range	0 to +70	−40 to +85	°C
2.5 V Power Supply Range (V_{CCA} and V_{CCI})	2.25 to 2.75	2.25 to 2.75	V
3.3 V Power Supply Range (V_{CCI})	3.0 to 3.6	3.0 to 3.6	V
5 V Power Supply Range (V_{CCI})	4.75 to 5.25	4.75 to 5.25	V

Typical SX-A Standby Current

Table 2-3 • Typical Standby Current for SX-A at 25°C with $V_{CCA} = 2.5$ V

Product	$V_{CCI} = 2.5$ V	$V_{CCI} = 3.3$ V	$V_{CCI} = 5$ V
A54SX08A	0.8 mA	1.0 mA	2.9 mA
A54SX16A	0.8 mA	1.0 mA	2.9 mA
A54SX32A	0.9 mA	1.0 mA	3.0 mA
A54SX72A	3.6 mA	3.8 mA	4.5 mA

Table 2-4 • Supply Voltages

V_{CCA}	V_{CCI}^*	Maximum Input Tolerance	Maximum Output Drive
2.5 V	2.5 V	5.75 V	2.7 V
2.5 V	3.3 V	5.75 V	3.6 V
2.5 V	5 V	5.75 V	5.25 V

Note: *3.3 V PCI is not 5 V tolerant due to the clamp diode, but instead is 3.3 V tolerant.

Electrical Specifications

Table 2-5 • 3.3 V LVTTTL and 5 V TTL Electrical Specifications

Symbol	Parameter		Commercial		Industrial		Units
			Min.	Max.	Min.	Max.	
V _{OH}	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OH} = −1 mA)	0.9 V _{CCI}		0.9 V _{CCI}		V
	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OH} = −8 mA)	2.4		2.4		V
V _{OL}	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OL} = 1 mA)	0.4		0.4		V
	V _{CCI} = Minimum V _I = V _{IH} or V _{IL}	(I _{OL} = 12 mA)	0.4		0.4		V
V _{IL}	Input Low Voltage		0.8		0.8		V
V _{IH}	Input High Voltage		2.0	5.75	2.0	5.75	V
I _{IL} /I _{IH}	Input Leakage Current, V _{IN} = V _{CCI} or GND		−10	10	−10	10	μA
I _{OZ}	Tristate Output Leakage Current		−10	10	−10	10	μA
t _R , t _F	Input Transition Time t _R , t _F		10		10		ns
C _{IO}	I/O Capacitance		10		10		pF
I _{CC}	Standby Current		10		20		mA
IV Curve*	Can be derived from the IBIS model on the web.						

Note: *The IBIS model can be found at <http://www.actel.com/download/libis/default.aspx>.

Table 2-6 • 2.5 V LVCMOS2 Electrical Specifications

Symbol	Parameter		Commercial		Industrial		Units
			Min.	Max.	Min.	Max.	
V _{OH}	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OH} = -100 μA)	2.1		2.1		V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OH} = -1 mA)	2.0		2.0		V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OH} = -2 mA)	1.7		1.7		V
V _{OL}	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OL} = 100 μA)		0.2		0.2	V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OL} = 1 mA)		0.4		0.4	V
	V _{DD} = MIN, V _I = V _{IH} or V _{IL}	(I _{OL} = 2 mA)		0.7		0.7	V
V _{IL}	Input Low Voltage, V _{OUT} ≤ V _{VOL(max)}		-0.3	0.7	-0.3	0.7	V
V _{IH}	Input High Voltage, V _{OUT} ≥ V _{VOH(min)}		1.7	5.75	1.7	5.75	V
I _{IL} /I _{IH}	Input Leakage Current, V _{IN} = V _{CCI} or GND		-10	10	-10	10	μA
I _{OZ}	Tristate Output Leakage Current, V _{OUT} = V _{CCI} or GND		-10	10	-10	10	μA
t _R , t _F	Input Transition Time t _R , t _F			10		10	ns
C _{IO}	I/O Capacitance			10		10	pF
I _{CC}	Standby Current			10		20	mA
IV Curve*	Can be derived from the IBIS model on the web.						

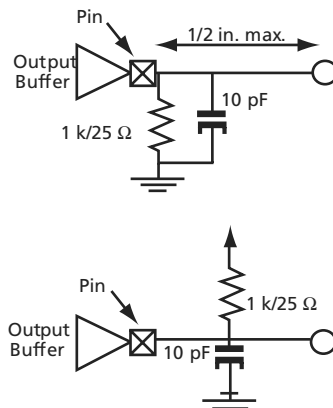
Note: *The IBIS model can be found at <http://www.actel.com/download/libis/default.aspx>.

Table 2-10 • AC Specifications (3.3 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 0.3V_{CCI}^1$	$-12V_{CCI}$	–	mA
		$0.3V_{CCI} \leq V_{OUT} < 0.9V_{CCI}^1$	$(-17.1(V_{CCI} - V_{OUT}))$	–	mA
		$0.7V_{CCI} < V_{OUT} < V_{CCI}^{1,2}$	–	EQ 2-3 on page 2-7	–
	(Test Point)	$V_{OUT} = 0.7V_{CC}^2$	–	$-32V_{CCI}$	mA
$I_{OL(AC)}$	Switching Current Low	$V_{CCI} > V_{OUT} \geq 0.6V_{CCI}^1$	$16V_{CCI}$	–	mA
		$0.6V_{CCI} > V_{OUT} > 0.1V_{CCI}^1$	$(26.7V_{OUT})$	–	mA
		$0.18V_{CCI} > V_{OUT} > 0^{1,2}$	–	EQ 2-4 on page 2-7	–
	(Test Point)	$V_{OUT} = 0.18V_{CC}^2$	–	$38V_{CCI}$	mA
I_{CL}	Low Clamp Current	$-3 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$	–	mA
I_{CH}	High Clamp Current	$V_{CCI} + 4 > V_{IN} \geq V_{CCI} + 1$	$25 + (V_{IN} - V_{CCI} - 1)/0.015$	–	mA
$slew_R$	Output Rise Slew Rate	$0.2V_{CCI} - 0.6V_{CCI}$ load ³	1	4	V/ns
$slew_F$	Output Fall Slew Rate	$0.6V_{CCI} - 0.2V_{CCI}$ load ³	1	4	V/ns

Notes:

1. Refer to the *VII* curves in Figure 2-2 on page 2-7. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.
2. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (C and D) are provided with the respective diagrams in Figure 2-2 on page 2-7. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
3. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per the latest revision of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is required (the maximum is no longer simply a guideline). Rise slew rate does not apply to open drain outputs.



To determine the heat sink's thermal performance, use the following equation:

$$\theta_{JA(TOTAL)} = \theta_{JC} + \theta_{CS} + \theta_{SA}$$

EQ 2-14

where:

$$\theta_{CS} = 0.37^{\circ}\text{C/W}$$

= thermal resistance of the interface material between the case and the heat sink, usually provided by the thermal interface manufacturer

$$\theta_{SA} = \text{thermal resistance of the heat sink in } ^{\circ}\text{C/W}$$

$$\theta_{SA} = \theta_{JA(TOTAL)} - \theta_{JC} - \theta_{CS}$$

EQ 2-15

$$\theta_{SA} = 13.33^{\circ}\text{C/W} - 3.20^{\circ}\text{C/W} - 0.37^{\circ}\text{C/W}$$

$$\theta_{SA} = 9.76^{\circ}\text{C/W}$$

A heat sink with a thermal resistance of 9.76°C/W or better should be used. Thermal resistance of heat sinks is a function of airflow. The heat sink performance can be significantly improved with the presence of airflow.

Carefully estimating thermal resistance is important in the long-term reliability of an Actel FPGA. Design engineers should always correlate the power consumption of the device with the maximum allowable power dissipation of the package selected for that device, using the provided thermal resistance data.

Note: The values may vary depending on the application.

Table 2-25 • A54SX16A Timing Characteristics

(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 2.25\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
2.5 V LVCMOS Output Module Timing ^{2, 3}												
t _{DLH}	Data-to-Pad Low to High		3.4		3.9		4.5		5.2		7.3	ns
t _{DHL}	Data-to-Pad High to Low		2.6		3.0		3.3		3.9		5.5	ns
t _{DHLS}	Data-to-Pad High to Low—low slew		11.6		13.4		15.2		17.9		25.0	ns
t _{ENZL}	Enable-to-Pad, Z to L		2.4		2.8		3.2		3.7		5.2	ns
t _{ENZLS}	Data-to-Pad, Z to L—low slew		11.8		13.7		15.5		18.2		25.5	ns
t _{ENZH}	Enable-to-Pad, Z to H		3.4		3.9		4.5		5.2		7.3	ns
t _{ENLZ}	Enable-to-Pad, L to Z		2.1		2.5		2.8		3.3		4.7	ns
t _{ENHZ}	Enable-to-Pad, H to Z		2.6		3.0		3.3		3.9		5.5	ns
d _{TLH} ⁴	Delta Low to High		0.031		0.037		0.043		0.051		0.071	ns/pF
d _{THL} ⁴	Delta High to Low		0.017		0.017		0.023		0.023		0.037	ns/pF
d _{THLS} ⁴	Delta High to Low—low slew		0.057		0.06		0.071		0.086		0.117	ns/pF

Note:

1. All –3 speed grades have been discontinued.
2. Delays based on 35 pF loading.
3. The equivalent IO Attribute settings for 2.5 V LVCMOS is 2.5 V LVTTTL in the software.
4. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[LH|HL|HLS]})$$
where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[LH|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.

Table 2-27 • A54SX16A Timing Characteristics
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High	2.2		2.5		2.8		3.3		4.6		ns
t _{DHL}	Data-to-Pad High to Low	2.8		3.2		3.6		4.2		5.9		ns
t _{ENZL}	Enable-to-Pad, Z to L	1.3		1.5		1.7		2.0		2.8		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.2		2.5		2.8		3.3		4.6		ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.0		3.5		3.9		4.6		6.4		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.8		3.2		3.6		4.2		5.9		ns
d _{TLH} ³	Delta Low to High	0.016		0.016		0.02		0.022		0.032		ns/pF
d _{THL} ³	Delta High to Low	0.026		0.03		0.032		0.04		0.052		ns/pF
5 V TTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad Low to High	2.2		2.5		2.8		3.3		4.6		ns
t _{DHL}	Data-to-Pad High to Low	2.8		3.2		3.6		4.2		5.9		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	6.7		7.7		8.7		10.2		14.3		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.7		3.2		4.5		ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew	7.4		8.4		9.5		11.0		15.4		ns
t _{ENZH}	Enable-to-Pad, Z to H	1.9		2.2		2.5		2.9		4.1		ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.6		4.2		4.7		5.6		7.8		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.5		2.9		3.3		3.9		5.4		ns
d _{TLH} ³	Delta Low to High	0.014		0.017		0.017		0.023		0.031		ns/pF
d _{THL} ³	Delta High to Low	0.023		0.029		0.031		0.037		0.051		ns/pF
d _{THLS} ³	Delta High to Low—low slew	0.043		0.046		0.057		0.066		0.089		ns/pF

Notes:

1. All –3 speed grades have been discontinued.
2. Delays based on 50 pF loading.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HL|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HL|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-28 • A54SX32A Timing Characteristics
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed ¹		-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays ²												
t _{PD}	Internal Array Module	0.8		0.9		1.1		1.2		1.7		ns
Predicted Routing Delays ³												
t _{DC}	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		0.1		ns
t _{FC}	FO = 1 Routing Delay, Fast Connect	0.3		0.3		0.3		0.4		0.6		ns
t _{RD1}	FO = 1 Routing Delay	0.3		0.3		0.4		0.5		0.6		ns
t _{RD2}	FO = 2 Routing Delay	0.4		0.5		0.5		0.6		0.8		ns
t _{RD3}	FO = 3 Routing Delay	0.5		0.6		0.7		0.8		1.1		ns
t _{RD4}	FO = 4 Routing Delay	0.7		0.8		0.9		1.0		1.4		ns
t _{RD8}	FO = 8 Routing Delay	1.2		1.4		1.5		1.8		2.5		ns
t _{RD12}	FO = 12 Routing Delay	1.7		2.0		2.2		2.6		3.6		ns
R-Cell Timing												
t _{RCO}	Sequential Clock-to-Q	0.6		0.7		0.8		0.9		1.3		ns
t _{CLR}	Asynchronous Clear-to-Q	0.5		0.6		0.6		0.8		1.0		ns
t _{PRESET}	Asynchronous Preset-to-Q	0.6		0.7		0.7		0.9		1.2		ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.6		0.7		0.8		0.9		1.2		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.2		1.4		1.5		1.8		2.5		ns
t _{RECASYN}	Asynchronous Recovery Time	0.3		0.4		0.4		0.5		0.7		ns
t _{HASYN}	Asynchronous Removal Time	0.3		0.3		0.3		0.4		0.6		ns
t _{MPW}	Clock Pulse Width	1.4		1.6		1.8		2.1		2.9		ns
Input Module Propagation Delays												
t _{INYH}	Input Data Pad to Y High 2.5 V LVCMOS	0.6		0.7		0.8		0.9		1.2		ns
t _{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS	1.2		1.3		1.5		1.8		2.5		ns
t _{INYH}	Input Data Pad to Y High 3.3 V PCI	0.5		0.6		0.6		0.7		1.0		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V PCI	0.6		0.7		0.8		0.9		1.3		ns
t _{INYH}	Input Data Pad to Y High 3.3 V LVTTTL	0.8		0.9		1.0		1.2		1.6		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V LVTTTL	1.4		1.6		1.8		2.2		3.0		ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-33 • **A54SX32A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
3.3 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High	1.9		2.2		2.4		2.9		4.0		ns
t _{DHL}	Data-to-Pad High to Low	2.0		2.3		2.6		3.1		4.3		ns
t _{ENZL}	Enable-to-Pad, Z to L	1.4		1.7		1.9		2.2		3.1		ns
t _{ENZH}	Enable-to-Pad, Z to H	1.9		2.2		2.4		2.9		4.0		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.5		2.8		3.2		3.8		5.3		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.0		2.3		2.6		3.1		4.3		ns
d _{TLH} ³	Delta Low to High	0.025		0.03		0.03		0.04		0.045		ns/pF
d _{THL} ³	Delta High to Low	0.015		0.015		0.015		0.015		0.025		ns/pF
3.3 V LVTTTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad Low to High	2.6		3.0		3.4		4.0		5.6		ns
t _{DHL}	Data-to-Pad High to Low	2.6		3.0		3.3		3.9		5.5		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	9.0		10.4		11.8		13.8		19.3		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.2		2.6		2.9		3.4		4.8		ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew	15.8		18.9		21.3		25.4		34.9		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.6		3.0		3.4		4.0		5.6		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.9		3.3		3.7		4.4		6.2		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.6		3.0		3.3		3.9		5.5		ns
d _{TLH} ³	Delta Low to High	0.025		0.03		0.03		0.04		0.045		ns/pF
d _{THL} ³	Delta High to Low	0.015		0.015		0.015		0.015		0.025		ns/pF
d _{THLS} ³	Delta High to Low—low slew	0.053		0.053		0.067		0.073		0.107		ns/pF

Notes:

1. All –3 speed grades have been discontinued.
2. Delays based on 10 pF loading and 25 Ω resistance.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HL|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HL|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-37 • A54SX72A Timing Characteristics (Continued)
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed*		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t_{QCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.7		1.9		2.2		2.5		3.5	ns
t_{QCHKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.7		2		2.2		2.6		3.6	ns
t_{QPWH}	Minimum Pulse Width High	1.5		1.7		2.0		2.3		3.2		ns
t_{QPWL}	Minimum Pulse Width Low	1.5		1.7		2.0		2.3		3.2		ns
t_{QCKSW}	Maximum Skew (Light Load)		0.2		0.3		0.3		0.3		0.5	ns
t_{QCKSW}	Maximum Skew (50% Load)		0.4		0.5		0.5		0.6		0.9	ns
t_{QCKSW}	Maximum Skew (100% Load)		0.4		0.5		0.5		0.6		0.9	ns

Note: *All –3 speed grades have been discontinued.

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
1	GND	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O	I/O
4	NC	I/O	I/O	I/O
5	I/O	I/O	I/O	I/O
6	NC	I/O	I/O	I/O
7	I/O	I/O	I/O	I/O
8	I/O	I/O	I/O	I/O
9	I/O	I/O	I/O	I/O
10	I/O	I/O	I/O	I/O
11	TMS	TMS	TMS	TMS
12	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
13	I/O	I/O	I/O	I/O
14	NC	I/O	I/O	I/O
15	I/O	I/O	I/O	I/O
16	I/O	I/O	I/O	I/O
17	NC	I/O	I/O	I/O
18	I/O	I/O	I/O	GND
19	I/O	I/O	I/O	V _{CCA}
20	NC	I/O	I/O	I/O
21	I/O	I/O	I/O	I/O
22	I/O	I/O	I/O	I/O
23	NC	I/O	I/O	I/O
24	I/O	I/O	I/O	I/O
25	NC	NC	NC	I/O
26	GND	GND	GND	GND
27	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
28	GND	GND	GND	GND
29	I/O	I/O	I/O	I/O
30	TRST, I/O	TRST, I/O	TRST, I/O	TRST, I/O
31	NC	I/O	I/O	I/O
32	I/O	I/O	I/O	I/O
33	I/O	I/O	I/O	I/O
34	I/O	I/O	I/O	I/O
35	NC	I/O	I/O	I/O

208-Pin PQFP				
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function	A54SX72A Function
36	I/O	I/O	I/O	I/O
37	I/O	I/O	I/O	I/O
38	I/O	I/O	I/O	I/O
39	NC	I/O	I/O	I/O
40	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
41	V _{CCA}	V _{CCA}	V _{CCA}	V _{CCA}
42	I/O	I/O	I/O	I/O
43	I/O	I/O	I/O	I/O
44	I/O	I/O	I/O	I/O
45	I/O	I/O	I/O	I/O
46	I/O	I/O	I/O	I/O
47	I/O	I/O	I/O	I/O
48	NC	I/O	I/O	I/O
49	I/O	I/O	I/O	I/O
50	NC	I/O	I/O	I/O
51	I/O	I/O	I/O	I/O
52	GND	GND	GND	GND
53	I/O	I/O	I/O	I/O
54	I/O	I/O	I/O	I/O
55	I/O	I/O	I/O	I/O
56	I/O	I/O	I/O	I/O
57	I/O	I/O	I/O	I/O
58	I/O	I/O	I/O	I/O
59	I/O	I/O	I/O	I/O
60	V _{CCI}	V _{CCI}	V _{CCI}	V _{CCI}
61	NC	I/O	I/O	I/O
62	I/O	I/O	I/O	I/O
63	I/O	I/O	I/O	I/O
64	NC	I/O	I/O	I/O
65	I/O	I/O	NC	I/O
66	I/O	I/O	I/O	I/O
67	NC	I/O	I/O	I/O
68	I/O	I/O	I/O	I/O
69	I/O	I/O	I/O	I/O
70	NC	I/O	I/O	I/O

329-Pin PBGA	
Pin Number	A54SX32A Function
D11	V _{CCA}
D12	NC
D13	I/O
D14	I/O
D15	I/O
D16	I/O
D17	I/O
D18	I/O
D19	I/O
D20	I/O
D21	I/O
D22	I/O
D23	I/O
E1	V _{CCI}
E2	I/O
E3	I/O
E4	I/O
E20	I/O
E21	I/O
E22	I/O
E23	I/O
F1	I/O
F2	TMS
F3	I/O
F4	I/O
F20	I/O
F21	I/O
F22	I/O
F23	I/O
G1	I/O
G2	I/O
G3	I/O
G4	I/O
G20	I/O
G21	I/O
G22	I/O
G23	GND

329-Pin PBGA	
Pin Number	A54SX32A Function
H1	I/O
H2	I/O
H3	I/O
H4	I/O
H20	V _{CCA}
H21	I/O
H22	I/O
H23	I/O
J1	NC
J2	I/O
J3	I/O
J4	I/O
J20	I/O
J21	I/O
J22	I/O
J23	I/O
K1	I/O
K2	I/O
K3	I/O
K4	I/O
K10	GND
K11	GND
K12	GND
K13	GND
K14	GND
K20	I/O
K21	I/O
K22	I/O
K23	I/O
L1	I/O
L2	I/O
L3	I/O
L4	NC
L10	GND
L11	GND
L12	GND
L13	GND

329-Pin PBGA	
Pin Number	A54SX32A Function
L14	GND
L20	NC
L21	I/O
L22	I/O
L23	NC
M1	I/O
M2	I/O
M3	I/O
M4	V _{CCA}
M10	GND
M11	GND
M12	GND
M13	GND
M14	GND
M20	V _{CCA}
M21	I/O
M22	I/O
M23	V _{CCI}
N1	I/O
N2	TRST, I/O
N3	I/O
N4	I/O
N10	GND
N11	GND
N12	GND
N13	GND
N14	GND
N20	NC
N21	I/O
N22	I/O
N23	I/O
P1	I/O
P2	I/O
P3	I/O
P4	I/O
P10	GND
P11	GND

329-Pin PBGA	
Pin Number	A54SX32A Function
P12	GND
P13	GND
P14	GND
P20	I/O
P21	I/O
P22	I/O
P23	I/O
R1	I/O
R2	I/O
R3	I/O
R4	I/O
R20	I/O
R21	I/O
R22	I/O
R23	I/O
T1	I/O
T2	I/O
T3	I/O
T4	I/O
T20	I/O
T21	I/O
T22	I/O
T23	I/O
U1	I/O
U2	I/O
U3	V _{CCA}
U4	I/O
U20	I/O
U21	V _{CCA}
U22	I/O
U23	I/O
V1	V _{CCI}
V2	I/O
V3	I/O
V4	I/O
V20	I/O
V21	I/O

256-Pin FBGA			
Pin Number	A545X16A Function	A545X32A Function	A545X72A Function
E11	I/O	I/O	I/O
E12	I/O	I/O	I/O
E13	NC	I/O	I/O
E14	I/O	I/O	I/O
E15	I/O	I/O	I/O
E16	I/O	I/O	I/O
F1	I/O	I/O	I/O
F2	I/O	I/O	I/O
F3	I/O	I/O	I/O
F4	TMS	TMS	TMS
F5	I/O	I/O	I/O
F6	I/O	I/O	I/O
F7	V _{CCI}	V _{CCI}	V _{CCI}
F8	V _{CCI}	V _{CCI}	V _{CCI}
F9	V _{CCI}	V _{CCI}	V _{CCI}
F10	V _{CCI}	V _{CCI}	V _{CCI}
F11	I/O	I/O	I/O
F12	V _{CCA}	V _{CCA}	V _{CCA}
F13	I/O	I/O	I/O
F14	I/O	I/O	I/O
F15	I/O	I/O	I/O
F16	I/O	I/O	I/O
G1	NC	I/O	I/O
G2	I/O	I/O	I/O
G3	NC	I/O	I/O
G4	I/O	I/O	I/O
G5	I/O	I/O	I/O
G6	V _{CCI}	V _{CCI}	V _{CCI}
G7	GND	GND	GND
G8	GND	GND	GND
G9	GND	GND	GND
G10	GND	GND	GND
G11	V _{CCI}	V _{CCI}	V _{CCI}
G12	I/O	I/O	I/O
G13	GND	GND	GND
G14	NC	I/O	I/O
G15	V _{CCA}	V _{CCA}	V _{CCA}

256-Pin FBGA			
Pin Number	A545X16A Function	A545X32A Function	A545X72A Function
G16	I/O	I/O	I/O
H1	I/O	I/O	I/O
H2	I/O	I/O	I/O
H3	V _{CCA}	V _{CCA}	V _{CCA}
H4	TRST, I/O	TRST, I/O	TRST, I/O
H5	I/O	I/O	I/O
H6	V _{CCI}	V _{CCI}	V _{CCI}
H7	GND	GND	GND
H8	GND	GND	GND
H9	GND	GND	GND
H10	GND	GND	GND
H11	V _{CCI}	V _{CCI}	V _{CCI}
H12	I/O	I/O	I/O
H13	I/O	I/O	I/O
H14	I/O	I/O	I/O
H15	I/O	I/O	I/O
H16	NC	I/O	I/O
J1	NC	I/O	I/O
J2	NC	I/O	I/O
J3	NC	I/O	I/O
J4	I/O	I/O	I/O
J5	I/O	I/O	I/O
J6	V _{CCI}	V _{CCI}	V _{CCI}
J7	GND	GND	GND
J8	GND	GND	GND
J9	GND	GND	GND
J10	GND	GND	GND
J11	V _{CCI}	V _{CCI}	V _{CCI}
J12	I/O	I/O	I/O
J13	I/O	I/O	I/O
J14	I/O	I/O	I/O
J15	I/O	I/O	I/O
J16	I/O	I/O	I/O
K1	I/O	I/O	I/O
K2	I/O	I/O	I/O
K3	NC	I/O	I/O
K4	V _{CCA}	V _{CCA}	V _{CCA}

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
C19	I/O	I/O
C20	V _{CCI}	V _{CCI}
C21	I/O	I/O
C22	I/O	I/O
C23	I/O	I/O
C24	I/O	I/O
C25	NC*	I/O
C26	NC*	I/O
D1	NC*	I/O
D2	TMS	TMS
D3	I/O	I/O
D4	V _{CCI}	V _{CCI}
D5	NC*	I/O
D6	TCK, I/O	TCK, I/O
D7	I/O	I/O
D8	I/O	I/O
D9	I/O	I/O
D10	I/O	I/O
D11	I/O	I/O
D12	I/O	QCLKC
D13	I/O	I/O
D14	I/O	I/O
D15	I/O	I/O
D16	I/O	I/O
D17	I/O	I/O
D18	I/O	I/O
D19	I/O	I/O
D20	I/O	I/O
D21	V _{CCI}	V _{CCI}
D22	GND	GND
D23	I/O	I/O
D24	I/O	I/O
D25	NC*	I/O
D26	NC*	I/O
E1	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
E2	NC*	I/O
E3	I/O	I/O
E4	I/O	I/O
E5	GND	GND
E6	TDI, IO	TDI, IO
E7	I/O	I/O
E8	I/O	I/O
E9	I/O	I/O
E10	I/O	I/O
E11	I/O	I/O
E12	I/O	I/O
E13	V _{CCA}	V _{CCA}
E14	CLKB	CLKB
E15	I/O	I/O
E16	I/O	I/O
E17	I/O	I/O
E18	I/O	I/O
E19	I/O	I/O
E20	I/O	I/O
E21	I/O	I/O
E22	I/O	I/O
E23	I/O	I/O
E24	I/O	I/O
E25	V _{CCI}	V _{CCI}
E26	GND	GND
F1	V _{CCI}	V _{CCI}
F2	NC*	I/O
F3	NC*	I/O
F4	I/O	I/O
F5	I/O	I/O
F22	I/O	I/O
F23	I/O	I/O
F24	I/O	I/O
F25	I/O	I/O
F26	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
G1	NC*	I/O
G2	NC*	I/O
G3	NC*	I/O
G4	I/O	I/O
G5	I/O	I/O
G22	I/O	I/O
G23	V _{CCA}	V _{CCA}
G24	I/O	I/O
G25	NC*	I/O
G26	NC*	I/O
H1	NC*	I/O
H2	NC*	I/O
H3	I/O	I/O
H4	I/O	I/O
H5	I/O	I/O
H22	I/O	I/O
H23	I/O	I/O
H24	I/O	I/O
H25	NC*	I/O
H26	NC*	I/O
J1	NC*	I/O
J2	NC*	I/O
J3	I/O	I/O
J4	I/O	I/O
J5	I/O	I/O
J22	I/O	I/O
J23	I/O	I/O
J24	I/O	I/O
J25	V _{CCI}	V _{CCI}
J26	NC*	I/O
K1	I/O	I/O
K2	V _{CCI}	V _{CCI}
K3	I/O	I/O
K4	I/O	I/O
K5	V _{CCA}	V _{CCA}

Note: *These pins must be left floating on the A54SX32A device.

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
K10	GND	GND
K11	GND	GND
K12	GND	GND
K13	GND	GND
K14	GND	GND
K15	GND	GND
K16	GND	GND
K17	GND	GND
K22	I/O	I/O
K23	I/O	I/O
K24	NC *	NC
K25	NC *	I/O
K26	NC *	I/O
L1	NC *	I/O
L2	NC *	I/O
L3	I/O	I/O
L4	I/O	I/O
L5	I/O	I/O
L10	GND	GND
L11	GND	GND
L12	GND	GND
L13	GND	GND
L14	GND	GND
L15	GND	GND
L16	GND	GND
L17	GND	GND
L22	I/O	I/O
L23	I/O	I/O
L24	I/O	I/O
L25	I/O	I/O
L26	I/O	I/O
M1	NC *	NC
M2	I/O	I/O
M3	I/O	I/O
M4	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
M5	I/O	I/O
M10	GND	GND
M11	GND	GND
M12	GND	GND
M13	GND	GND
M14	GND	GND
M15	GND	GND
M16	GND	GND
M17	GND	GND
M22	I/O	I/O
M23	I/O	I/O
M24	I/O	I/O
M25	NC *	I/O
M26	NC *	I/O
N1	I/O	I/O
N2	V _{CCI}	V _{CCI}
N3	I/O	I/O
N4	I/O	I/O
N5	I/O	I/O
N10	GND	GND
N11	GND	GND
N12	GND	GND
N13	GND	GND
N14	GND	GND
N15	GND	GND
N16	GND	GND
N17	GND	GND
N22	V _{CCA}	V _{CCA}
N23	I/O	I/O
N24	I/O	I/O
N25	I/O	I/O
N26	NC *	NC
P1	NC *	I/O
P2	NC *	I/O
P3	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
P4	I/O	I/O
P5	V _{CCA}	V _{CCA}
P10	GND	GND
P11	GND	GND
P12	GND	GND
P13	GND	GND
P14	GND	GND
P15	GND	GND
P16	GND	GND
P17	GND	GND
P22	I/O	I/O
P23	I/O	I/O
P24	V _{CCI}	V _{CCI}
P25	I/O	I/O
P26	I/O	I/O
R1	NC *	I/O
R2	NC *	I/O
R3	I/O	I/O
R4	I/O	I/O
R5	TRST, I/O	TRST, I/O
R10	GND	GND
R11	GND	GND
R12	GND	GND
R13	GND	GND
R14	GND	GND
R15	GND	GND
R16	GND	GND
R17	GND	GND
R22	I/O	I/O
R23	I/O	I/O
R24	I/O	I/O
R25	NC *	I/O
R26	NC *	I/O
T1	NC *	I/O
T2	NC *	I/O

Note: *These pins must be left floating on the A54SX32A device.

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
T3	I/O	I/O
T4	I/O	I/O
T5	I/O	I/O
T10	GND	GND
T11	GND	GND
T12	GND	GND
T13	GND	GND
T14	GND	GND
T15	GND	GND
T16	GND	GND
T17	GND	GND
T22	I/O	I/O
T23	I/O	I/O
T24	I/O	I/O
T25	NC *	I/O
T26	NC *	I/O
U1	I/O	I/O
U2	V _{CCI}	V _{CCI}
U3	I/O	I/O
U4	I/O	I/O
U5	I/O	I/O
U10	GND	GND
U11	GND	GND
U12	GND	GND
U13	GND	GND
U14	GND	GND
U15	GND	GND
U16	GND	GND
U17	GND	GND
U22	I/O	I/O
U23	I/O	I/O
U24	I/O	I/O
U25	V _{CCI}	V _{CCI}
U26	I/O	I/O
V1	NC *	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
V2	NC *	I/O
V3	I/O	I/O
V4	I/O	I/O
V5	I/O	I/O
V22	V _{CCA}	V _{CCA}
V23	I/O	I/O
V24	I/O	I/O
V25	NC *	I/O
V26	NC *	I/O
W1	I/O	I/O
W2	I/O	I/O
W3	I/O	I/O
W4	I/O	I/O
W5	I/O	I/O
W22	I/O	I/O
W23	V _{CCA}	V _{CCA}
W24	I/O	I/O
W25	NC *	I/O
W26	NC *	I/O
Y1	NC *	I/O
Y2	NC *	I/O
Y3	I/O	I/O
Y4	I/O	I/O
Y5	NC *	I/O
Y22	I/O	I/O
Y23	I/O	I/O
Y24	V _{CCI}	V _{CCI}
Y25	I/O	I/O
Y26	I/O	I/O

Note: *These pins must be left floating on the A54SX32A device.

Datasheet Information

List of Changes

The following table lists critical changes that were made in the current version of the document.

Previous Version	Changes in Current Version (v5.3)	Page
v5.2 (June 2006)	–3 speed grades have been discontinued.	N/A
	The "SX-A Timing Model" was updated with –2 data.	2-14
v5.1 February 2005	RoHS information was added to the "Ordering Information".	ii
	The "Programming" section was updated.	1-13
v5.0	Revised Table 1 and the timing data to reflect the phase out of the –3 speed grade for the A54SX08A device.	i
	The "Thermal Characteristics" section was updated.	2-11
	The "176-Pin TQFP" was updated to add pins 81 to 90.	3-11
	The "484-Pin FBGA" was updated to add pins R4 to Y26	3-26
v4.0	The "Temperature Grade Offering" is new.	1-iii
	The "Speed Grade and Temperature Grade Matrix" is new.	1-iii
	"SX-A Family Architecture" was updated.	1-1
	"Clock Resources" was updated.	1-5
	"User Security" was updated.	1-7
	"Power-Up/Down and Hot Swapping" was updated.	1-7
	"Dedicated Mode" is new	1-9
	Table 1-5 is new.	1-9
	"JTAG Instructions" is new	1-10
	"Design Considerations" was updated.	1-12
	The "Programming" section is new.	1-13
	"Design Environment" was updated.	1-13
	"Pin Description" was updated.	1-15
	Table 2-1 was updated.	2-1
	Table 2-2 was updated.	2-1
	Table 2-3 is new.	2-1
	Table 2-4 is new.	2-1
	Table 2-5 was updated.	2-2
	Table 2-6 was updated.	2-2
	"Power Dissipation" is new.	2-8
	Table 2-11 was updated.	2-9